

FIG. 2



US-PAT-NO: 6366524

DOCUMENT-IDENTIFIER: US 6366524 B1

TITLE: Address decoding in
multiple-bank memory architectures

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Abstract Text - ABTX (1):

Methods and apparatus for decoding an externally-applied address in a synchronous memory device are arranged to decode a first portion of the address during a setup time and to decode a second portion of the address following the setup time. The first portion of the address may be indicative of a bank address of a multiple-bank memory device. The second portion of the address may be indicative of row and column addresses within a bank of the multiple-bank memory device. Decoding of the first portion of the address is performed by an address input buffer stage having a decoder interposed between the input buffers and the address latches, such that the decoder generally replaces a delay stage of a typical input buffer stage. As such, the first portion of the address is decoded during a setup time. By decoding the first portion of the address during a setup time, it is available to direct the

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US006366524B1

United States Patent
Abdifard(10) Patent No.: US 6,366,524 B1
(45) Date of Patent: Apr. 2, 2002ADDRESS DECODING IN MULTIPLE-BANK
MEMORY ARCHITECTURESInventor: Ebrahim Abdifard, Sunnyvale, CA
(US)Assignee: Micron Technology Inc., Boise, ID
(US)Notice: Subject to any disclaimer, the term of this
patent is extended or adjusted under 35
U.S.C. 154(b) by 0 days.

App. No.: 08/618,197

Filed: Jan. 28, 2000

Int. Cl. G11C 8/00

U.S. Cl. 365/230.06; 365/230.03;
365/230.08Field of Search 365/230.06, 230.03,
365/230.06, 185.11

References Cited

U.S. PATENT DOCUMENTS

- | | | | |
|-----------|---------|-------------------|------------|
| 541,886 A | 8/1991 | Lee | |
| 202,623 A | 4/1995 | Stamogova et al. | 365/230.06 |
| 293,117 A | 3/1995 | Papaya et al. | 365/230.06 |
| 537,354 A | 7/1996 | Mochimaru et al. | |
| 600,658 A | 3/1997 | Schaefer | |
| 566,372 A | 3/1997 | Schaefer | |
| 748,557 A | 3/1998 | Kang | 365/230.08 |
| 751,039 A | 5/1998 | Kazifman et al. | |
| 787,487 A | 7/1998 | Miller et al. | |
| 954,908 A | 8/1999 | Jiang et al. | |
| 590,219 A | 6/1999 | Rao | 365/230.03 |
| 595,458 A | 11/1999 | Jiang et al. | |
| 626,445 A | 3/2000 | Mills et al. | |
| 137,438 A | 10/2000 | Kazifman et al. | |
| 141,247 A | 10/2000 | Reisgarber et al. | |

6,166,993 A * 12/2000 Yamashita 365/230.03

OTHER PUBLICATIONS

Koeth et al., "DRAM circuit design: a tutorial," IEEE Prom.
2001, pp. 14-23, 142-153.
Micron Semiconductor Products, Inc., "2Mb Smart 5 BIO-
S-Optimized Boot Block Flash Memory," Flash Memory
www.micron.com, copyright 2000, Micron Technology,
Inc., pp. 1-12.
Micron, "16 Mbit x16 SDRAM" Synchronous DRAM, www-
micron.com, copyright 1999 Micron Technology, Inc., pp.
1-41.

* cited by examiner

Primary Examiner—Huan Hoang
(74) Attorney, Agent, or Firm—Egg Silver Polglaze LeBar
& Jay, P.A.

(57) ABSTRACT

Methods and apparatus for decoding an externally-applied address in a synchronous memory device are arranged to decode a first portion of the address during a setup time and to decode a second portion of the address following the setup time. The first portion of the address may be indicative of a bank address of a multiple-bank memory device. The second portion of the address may be indicative of row and column addresses within a bank of the multiple-bank memory device. Decoding of the first portion of the address is performed by an address input buffer stage having a decoder interposed between the input buffers and the address latches, such that the decoder generally replaces a delay stage of a typical input buffer stage. As such, the first portion of the address is decoded during a setup time. By decoding the first portion of the address during a setup time, it is available to direct the second portion of the address to a proper decoder substantially without delay.

46 Claims, 8 Drawing Sheets

☒ Details ☒ Text ☒ Image ☒ HTML Full

FAST - [1.wsp:1]

File View Edit Tools Window Help

L8: (19) 7 and address

L9: (5) 8 not 5

L10: (46) 2 and address

L12: (52) 10 or 11

L13: (13) 12 and more

L11: (15) 2 and address

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	U	1	Document ID	Issue Date	Pages	Title	Current OR	Current XRef	R
6	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6215709 B1	20010410	89	Synchronous dynamic random access memory device	365/189.11	365/189.09; 365/194;	
7	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6212111 B1	20010403	89	Synchronous dynamic random access memory device	365/200	365/189.07	
8	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6172935 B1	20010109	90	Synchronous dynamic random access memory device	365/233	365/194; 365/230.08	
9	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6125432 A	20000926		Image process apparatus having a storage device with	711/157	345/545; 345/572;	
10	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6005592 A	19991221		Image processing apparatus having improved memory	345/571	345/531	
11	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 5953738 A	19990914	22	DRAM with integral SRAM and arithmetic-logic units	711/105	711/114; 711/5	
12	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 5808948 A	19980915	9	Semiconductor memory device	365/201	365/200; 365/230.03	
13	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 5761694 A	19980602		Multi-bank memory system and method having addresses	711/5	365/230.03; 365/230.06;	
14	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 5313624 A	19940517		DRAM multiplexer	714/6	714/763	
15	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 4473877 A	19840925		Parasitic memory expansion for computers	711/2		

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FAST [11.wsp 11]

File View Edit Tools Window Help

☒ L8: (19) 7 and addr
☒ L9: (5) 8 not 5
☒ L10: (46) 2 and add
☒ L12: (52) 10 or 11
☒ L13: (13) 12 and mo
☒ L11: (15) 2 and add
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	U	I	Document ID	Issue Date	Pages	Title	Current OR	Current XRef	R
1	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 20010050860 A1	20011213	37	Non-volatile memory with background operation	365/185.11		
2	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6373752 B1	20020416	88	Synchronous dynamic random access memory device	365/189.05	365/189.11; 365/230.06;	
3	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6351404 B1	20020226	88	Synchronous dynamic random access memory device	365/51	365/63	
4	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6333889 B1	20011225		Logic-merged semiconductor memory having high internal	365/230.03	365/51; 365/63;	
5	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6215726 B1	20010410	23	Semiconductor device with internal clock generating	365/233	327/141; 327/155;	
6	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6215709 B1	20010410	89	Synchronous dynamic random access memory device	365/189.11	365/189.09; 365/194;	
7	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6212111 B1	20010403	89	Synchronous dynamic random access memory device	365/200	365/189.07	
8	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6172935 B1	20010109	90	Synchronous dynamic random access memory device	365/233	365/194; 365/230.08	
9	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6125432 A	20000926		Image process apparatus having a storage device with	711/157	345/545; 345/572;	
10	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6005592 A	19991221		Image processing apparatus having improved memory	345/571	345/531	
11	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 5953738 A	19990914	22	DRAM with integral SRAM and arithmetic-logic units	711/105	711/114; 711/5	

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rows in all of the banks 20 within the SDRAM 10. Examples of other well known commands include, but are not limited to, the ACTIVE, READ, WRITE, BURST TERMINATE, AUTO REFRESH, LOAD MODE REGISTER, COMMAND INHIBIT and NOP commands.

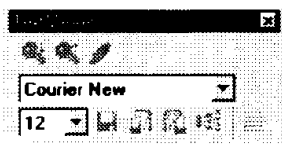
(13) The ACTIVE command is used to open up (or activate) a row of memory cells in a particular bank 20 for a subsequent access. The row remains active until a PRECHARGE command deactivates it. The READ command is used to initiate a burst read access for an active row. The WRITE command is used to initiate a burst write access for an active row. The READ and WRITE commands will also be accompanied with the column and bank addresses to complete the addressing for the command. The AUTO REFRESH command is used to refresh the contents of the memory arrays 20. The BURST TERMINATE command is used to truncate a read burst. The LOAD MODE REGISTER allows a mode register of the control circuit 12 to be loaded. The mode register contains information such as burst length and

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The diagram illustrates a memory system (10) with the following components and connections:

- Memory Banks (20):** Represented as a vertical column of blocks on the left.
- Sense Amplifiers (16):** A vertical column of blocks to the right of the memory banks, connected to them via bidirectional arrows.
- Input/Output Circuit (30):** A block to the right of the sense amplifiers, connected to them via bidirectional arrows.
- Column Decoders (18):** A vertical column of blocks to the right of the I/O circuit, connected to it via bidirectional arrows.
- Row Decoders (14):** A block below the memory banks, connected to them via bidirectional arrows.
- Control Circuit (12):** A block below the row decoders, connected to them via a bidirectional arrow.
- Addressing Circuit:** A block to the right of the control circuit, connected to it via a bidirectional arrow.
- Data Bus:** At the top, a horizontal line with arrows labeled "D00-D07" and "D08" indicates data flow between the I/O circuit and the column decoders.
- Addressing:** Arrows from the control circuit and the addressing circuit point towards the row decoders and column decoders, respectively, indicating the input of row and column addresses.

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Schaefer

[45] Date of Patent: *Aug. 29, 2000

[54] SYNCHRONOUS DRAM MEMORY WITH ASYNCHRONOUS COLUMN DECODE

[72] Inventor: Scott Schaefer, Boise, ID

[73] Assignee: Micron Technology, Inc., Boise, ID

[*] Notice: This patent is subject to a terminal disclaimer.

[31] Appl. No.: 08/318,449

[21] Filed: May 24, 1999

Related U.S. Application Data

[62] Continuation of application No. 08/926,940, Sep. 10, 1997 which is a continuation of application No. 08/772,873, Dec. 28, 1996, Pat. No. 5,751,676, which is a continuation of application No. 08/072,869, Sep. 1, 1993, Pat. No. 5,600,000.

[51] Int. Cl.: G11C 8/00

[52] U.S. Cl.: 365/233.5, 365/233

[56] Field of Search: 365/233.5, 233, 365/232, 237/28

References Cited

U.S. PATENT DOCUMENTS

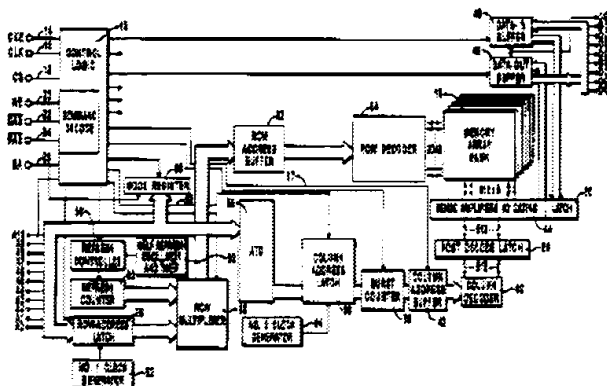
4,712,602	1/1988	Ng	365/230
4,912,675	9/1990	Baloda	365/233.5
4,942,376	7/1990	Wang	365/233.5
4,972,374	11/1990	Wang	365/233.5
5,047,964	9/1991	Boender	365/233

Primary Examiner—A. Lashin
Attorney, Agent, or Firm—Wolfgang, Nydegger & Sealey

ABSTRACT

Disclosed is a synchronous DRAM memory module with control circuitry that allows the memory module to operate partially asynchronously. Specifically, a circuit is disclosed which enables address translation decoders to begin decoding the column address immediately after a new column address is present on the address bus line and without waiting for the column address strobe signal to synchronize with the rising or falling edge of the synchronizing clock signal. Also disclosed is a manner of controlling the latching circuitry whereby such new column addresses may be decoded and held within a buffer until the column address strobe signal catches the circuitry that the column address is correct and is to be input into the microprocessor. Thus, each new column address will be decoded immediately after it is present on the address bus and subsequent column addresses will be discarded, while desired column addresses are input into the memory array bank immediately upon the presence of the column address strobe which denotes that the column address is valid. The present invention improves the access times of read and write operations in synchronous DRAM memory by up to a complete clock cycle.

46 Claims, 6 Drawing Sheets



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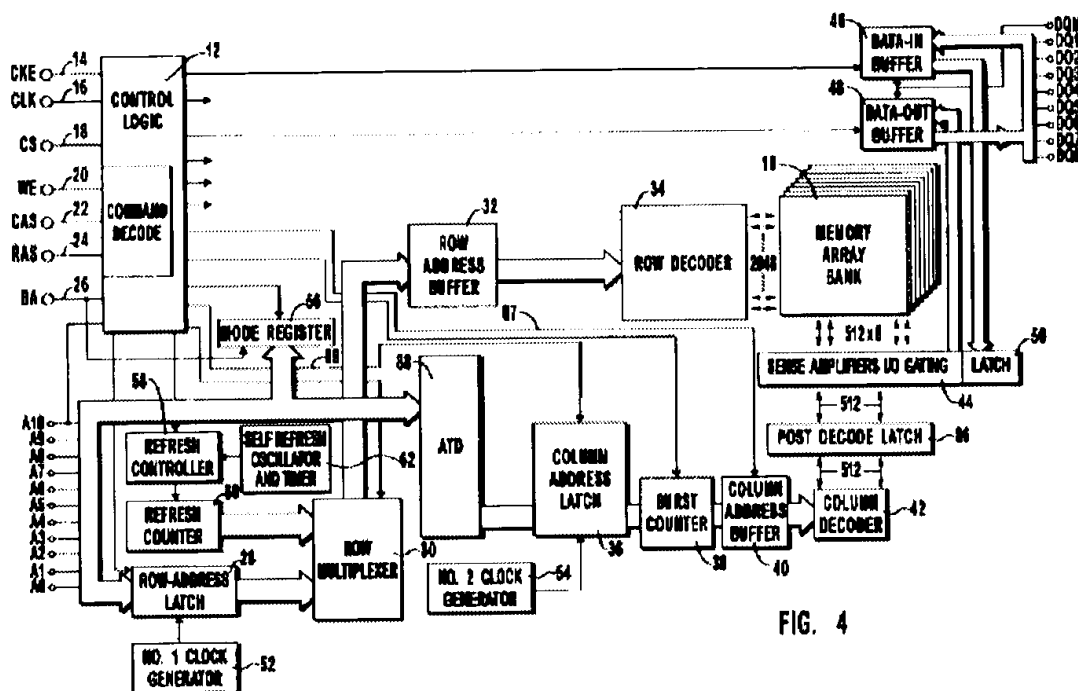


FIG. 4

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Jun. 15, 1999

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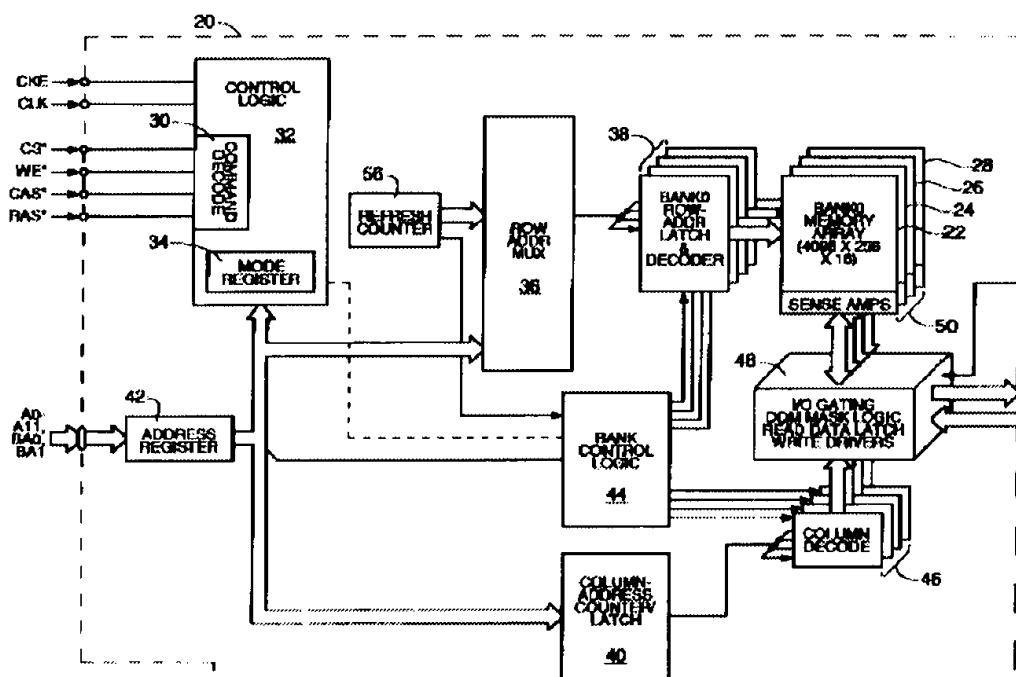


FIG. 1A

FIGURE 1B

U.S. Patent

Aug. 21, 2001

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US 6,278,648 B1

